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| Notice of References Cited | Application/Control No. 09/966,458 | Applicant(s)/Patent Under Reexamination WANG ET AL. | |
| | Examiner Michael J. Yigdall | Art Unit 2122 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|-----------------|----------------|
| | A | US-6,134,710 A | 10-2000 | Levine et al. | 717/158 |
| | B | US-6,549,930 B1 | 04-2003 | Chrysos et al. | 718/104 |
| | C | US-5,996,092 A | 11-1999 | Augsburg et al. | 714/38 |
| | D | US-6,374,367 B1 | 04-2002 | Dean et al. | 714/37 |
| | E | US- | | | |
| | F | US- | | | |
| | G | US- | | | |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
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| | P | | | | | |
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NON-PATENT DOCUMENTS

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|---|---|---|
| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
| | U | |
| | V | |
| | W | |
| | X | |

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